2024년 1월 **24**일(수)-**26**일(금) | 경주화백컨벤션센터(HICO)

2024년 1월 25일(목), 15:30-17:15 Room K(205),2층

G. Device & Process Modeling, Simulation and Reliability 분과 [TK3-G] TCAD & Multiphysics Simulation

좌장: 이재우 교수(고려대학교), 김현우 교수(건국대학교)

	작성. 이제후 포우(고더대역포), 검연후 포우(건축대역포)
TK3-G-1 15:30-15:45	The Quantum Mechanical Effect of Amorphous InGaZnO Transistors
	Compared with Silicon-on Insulator Transistors
	Ho Jung Lee, Donguk Kim, Changwook Kim, Dong Myong Kim, Sung-Jin Choi,
	Jong-Ho Bae, and Dae Hwan Kim
	School of Electrical Engineering, Kookmin University
	Investigating Radioactive Ions Effect in The Complementary FET
TK3-G-2	based on The Structure
15:45-16:00	Jonghwa Jeong and Hyunwoo Kim
	Department of Electrical and Electronics Engineering, Konkuk University
	Mitigation of Single Event Upset Effects in 3 nm Technology Node
TK3-G-3	Gate-All-Around Nanosheet FET 6T SRAM cell
16:00-16:15	Minji Bang, Jonghyeon Ha, Minki Suh, Dabok Lee, Minsang Ryu, and Jungsik Kim
	Department of Electrical Engineering, Gyeongsang National University
	A Novel CT-DRAM with High Speed and High Retention at Low Power
TK3-G-4	to Replace DRAM
16:15-16:30	Dabok Lee, Jonghyeon Ha, Minki Suh, Minji Bang, Minsang Ryu, and Jungsik Kim
	Department of Electrical Engineering, Gyeongsang National University
	Investigation of Filamentary Resistive Switching Using Finite Element
TK3-G-5	Method with Phase-field and Multiphysics Simulation
16:30-16:45	Dongmyung Jung and Yongwoo Kwon
	Department of Materials Science and Engineering, Hongik University
	Computational Investigation on Quantum Information Processing
TK3-G-6	Using Triple Quantum Dot Structures
16:45-17:00	Ji-Hoon Kang and Hoon Ryu
	KISTI
	Multiphysics Modeling of Thermal Disturbance in Three-Dimensional
TK3-G-7	Stackable Phase-Change Memory
17:00-17:15	Yechan Kim ¹ , Namwook Hur ² , Joonki Suh ² , and Yongwoo Kwon ¹
	¹ Hongik University, ² Ulsan National Institute of Science and Technology
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